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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/823,729	04/14/2004	Takashi Watanabe	042341	5344
38834 7590 01/25/2008 WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP 1250 CONNECTICUT AVENUE, NW SUITE 700 WASHINGTON, DC 20036			EXAMINER	
			VU, DAVID	
			ART UNIT	PAPER NUMBER
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			MAIL DATE	DELIVERY MODE
			01/25/2008	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

	Application No.	Applicant(s)	•			
	10/823,729	WATANABE ET AL.				
Office Action Summary	Examiner	Art Unit				
	DAVID VU	2818				
The MAILING DATE of this communication a	appears on the cover sheet wi	th the correspondence address				
Period for Reply	DIVIO OET TO EVOIDE AM	ONTUKO) EDOM				
A SHORTENED STATUTORY PERIOD FOR REI THE MAILING DATE OF THIS COMMUNICATIOI - Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a - If NO period for reply is specified above, the maximum statutory peri - Failure to reply within the set or extended period for reply will, by sta Any reply received by the Office later than three months after the may earned patent term adjustment. See 37 CFR 1.704(b).	N. 1.136(a). In no event, however, may a reply within the statutory minimum of third will expire SIX (6) MON tute, cause the application to become AB	eply be timely filed y (30) days will be considered timely. THS from the mailing date of this communication. ANDONED (35 U.S.C. § 133).	•			
Status						
1)⊠ Responsive to communication(s) filed on 31	October 2007.					
	his action is non-final.					
,	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims						
4)⊠ Claim(s) <u>1-4,12,13,28,29 and 34</u> is/are pend	ding in the application.	•				
· · · · · · · · · · · · · · · · · · ·	4a) Of the above claim(s) is/are withdrawn from consideration.					
5) Claim(s) is/are allowed.						
6) Claim(s) 1-4,12,13,28,29 and 34 is/are rejection	cted.					
7) Claim(s) is/are objected to.						
8) Claim(s) are subject to restriction and	d/or election requirement.					
Application Papers						
9) The specification is objected to by the Exam	iner.					
10)⊠ The drawing(s) filed on <u>14 April 2004</u> is/are: a)⊠ accepted or b)□ objected to by the Examiner.						
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).						
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).						
11) The oath or declaration is objected to by the	Examiner. Note the attached	Office Action or form PTO-152.				
Priority under 35 U.S.C. § 119						
12)⊠ Acknowledgment is made of a claim for fore	ian priority under 35 U.S.C. §	. 119(a)-(d) or (f).				
a)⊠ All b)□ Some * c)□ None of:						
,,	·					
2. Certified copies of the priority docume	ents have been received in A	pplication No				
3. Copies of the certified copies of the p		received in this National Stage				
application from the International Bure	, , , , , , , , , , , , , , , , , , , ,					
* See the attached detailed Office action for a l	ist of the certified copies not	received.				
Attachment(s)						
1) Notice of References Cited (PTO-892)	4) Interview S	Summary (PTO-413)				
2) Notice of Draftsperson's Patent Drawing Review (PTO-948)		s)/Mail Date nformal Patent Application (PTO-152)				
Information Disclosure Statement(s) (PTO-1449 or PTO/SB/Paper No(s)/Mail Date	6) Other:					

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DETAILED ACTION

Continued Examination Under 37 CFR 1.914

1. A request for continued examination under 37 CFR 1.114, including the, fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on October 31, 2007 has been entered.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claims 1-4, 12, 13, 28 and 29 are rejected under 35 U. S. C. 102(e) as being anticipated by Miyashita et al. (US Pat. 5,861,054, hereinafter Miyashita).

Regarding claims 1-4 and 28-29, Miyashita discloses in figs. 5A-5J a semiconductor device fabrication method comprising the steps of: polishing the surface of a film-to-be-polished 12 formed over a semiconductor substrate 1 by first polishing slurry/CMP process (col. 8, lines 11-20 and fig. 5H); and after the surface of the film-to-be-polished 12 has been planarized,

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further polishing the surface of the film-to-be-polished 12 by second polishing slurry/CMP process one more time (col. 8, lines 26-31 and fig. 5J), the polishing slurry contained in the second polishing material being the same kind as the polishing slurry of the first polishing material. Note that the CMP method is characterized by polishing a wafer surface with an abrasive cloth (pad) while supplying a polishing solution (slurry) mixed with abrasive grains. {See **Koutny**, **Jr et al.** (US 6,171,180) (col. 1, line 60 through col. 2, line 17 or **Hsu et al.** (US 6,677,239) (col. 1, lines 40-49; col. 10, lines 18-24 and **Wang** (US 6,046,112) (col. 6, lines 13-17)}.

Regarding claims 12 and 13, Miyashita discloses in figs. 5A-5G that before the step of planarizing the surface of the film-to-be-polished, the steps of: forming over the semiconductor substrate 1 an insulation film 2/8 having polish characteristics different from those of the film-to-be-polished 12; forming an opening in the insulation film 2/8; etching the semiconductor substrate 1 with the insulation film 2/8 as a mask to form a trench in the semiconductor substrate 1; and forming the film-to-be-polished 12 in the trench and over the insulation film 2/8, in the step of further polishing the surface of the film-to-be-polished 12, the surface of the film-to-be-polished 12 is polished with the insulation film 2 as a stopper (fig. 13).

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill

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in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).

3. Claim 34 is rejected under 35 U.S.C. 103 (a) as being unpatentable over by Miyashita (US Pat. 5,861,054).

Miyashita fails to disclose the ratio of a supply amount of the second polishing material of the polishing slurry to a supply amount of the water is 1:5. Although the exact ratio of polishing slurry:water was not specified as recited in claim 34, it appears that the ratio as claimed is prima facie obvious due to the fact that one can vary the amount of polishing slurry and water to achieve a specific stable compound. This claim is prima facie obvious without showing that the claimed ranges achieve unexpected results relative to the prior art range. In re Woodruff, 16 USPQ2d 1935, 1937 (Fed. Cir. 1990). See also In re Huang, 40 USPQ2d 1685, 1688 (Fed. Cir. 1996) (claimed ranges of a result effective variable, which do not overlap the prior art ranges, are unpatentable unless they produce a new and unexpected result which is different in kind and not merely in degree from the results of the prior art). See also In re Boesch, 205 USPQ 215 (CCPA) (discovery of optimum value of result effective variable in known process is ordinarily within

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skill of art) and In re Aller, 105 USPQ 233 (CCPA 1955) (selection of optimum ranges within prior art general conditions is obvious).

Response to Arguments

4. Applicant's arguments with respect to claims 1-4, 12, 13, 28 and 29 have been considered but are most in view of the new ground(s) of rejection.

Conclusion

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to David Vu whose telephone number is (571) 272-1798. The examiner can normally be reached on Monday-Friday from 8:00am to 5:00pm. If attempt to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Steven Loke H can be reached on (571) 272-1657. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR, Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

DAVID VU PRIMARY EXAMINER